

■ Public Beamlines

No.	Beamline name	Research areas
Experimental station/system		
Light source (energy range at sample position, etc.)		
1	BL01B1 : XAFS I	Wide energy range (3.8-113 keV), XAFS of dilute systems and thin films, Time-resolved XAFS by quick scan (time-resolved QXAFS), Depth-resolved XAFS, XAFS at low and high temperatures, Simultaneous XAFS and XRD measurements, Simultaneous XAFS and IR measurements
	XAFS measurement system, Ionization chambers, Lytle detector, 19-element Ge solid-state detector, Conversion electron yield (CEY) detector, Two-dimensional X-ray detector PILATUS, Electric furnace (1000 °C), Cryostat (4 K), Gas supply and detoxifying system, Fourier transform infrared (FT-IR) spectrometer (4000cm ⁻¹ ~500cm ⁻¹), Bending magnet (3.8-113 keV)	
2	BL02B1 : Single Crystal Structural Analysis	Charge density study using high energy X-ray, In-situ single crystal experiments, Micro crystal structure analysis
	Hybrid photon counting detector, Large cylindrical imaging plate camera. (Please contact the beamline scientist, if you submit the beamline proposal for the first time and want to use own experimental devices.) Bending magnet (8-115 keV)	
3	BL02B2 : Powder Diffraction	Charge density study from powder diffraction, Structural phase transition, <i>Ab initio</i> structure determination from powder diffraction, Crystal structure refinement by Rietveld method, In situ powder diffraction experiment under gas and vapor adsorption/desorption
	Automatic powder diffraction experiment (50 samples : 90 - 1100 K). Diffractometer for powder diffraction with MYTHEN micro-strip x-ray detector, Large Debye-Scherrer camera with imaging plate. Please contact to the responsible beamline scientist, if you want to do extremely low-temperature using cryostat (< 100 K), high temperature using furnace (<1300 K, Heating stage< 1647K), and In situ powder X-ray diffraction experiment under gas and vapor adsorption/desorption. Bending magnet (12-37 keV)	
4	BL04B1 : High Temperature and High Pressure Research	X-ray diffraction measurements and radiography under extreme conditions using large-volume press
	Large-volume press (SPEED-1500, SPEED-Mk.II), AC/DC power supply for resistance heating, Energy-dispersive X-ray diffractometer, 2D X-ray CCD detector, High-speed CCD camera, Ultrasonic velocity measurement system, Bending magnet [white, 20-150 keV; Si(111), 30-60 keV]	
5	BL04B2 : High Energy X-ray Diffraction	Structural analysis of glass, liquid, and amorphous materials
	High-throughput PDF measurement system, automatic sample-exchanger (50 samples, 100-1100 K), low/high temperature system with nitrogen gas blowing, X-ray PDF diffractometer and area flat panel detector for amorphous materials (Cryostat (20 K-RT), high-temperature furnace (~1,300 K), Aerodynamic levitation system (1,200~3,200 K)) Bending magnet [Si(511) 113 keV; Si(220), 61.4 keV]	

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6	BL08W : High Energy Inelastic Scattering	Magnetic Compton scattering, High-resolution Compton scattering, Compton scattering imaging, High-energy X-ray scattering, High-energy X-ray fluorescence analysis (XRF), Time-resolved pair distribution function analysis (PDF) Magnetic Compton scattering spectrometer, High-resolution Compton scattering spectrometer, High-energy X-ray fluorescence spectrometer, Flat area panel detector, Elliptical multipole wiggler (Station A, 110-300 keV; Station B, 100-210 keV)
7	BL09XU : HAXPES I	Resonant hard X-ray photoelectron spectroscopy(HAXPES), Polarization-dependent HAXPES using diamond phase retarder, Depth analysis of electron state, Materials science and applied materials science • In-vacuum undulator (4.9-100 keV) • Double channel cut monochromator(DCCM): Si 220 x 2, Si 311 x 2 (hn=4.9-12 keV, Tunable photon energy) / CCM Si 333,444,555 (hn=6,8,10 keV, Fixed energy) • Double X-ray phase retarder: Polarization change (hn=5.9-9.5 keV) • Experimental hutch 1: High-energy-resolution photoelectron spectroscopy by hard X-ray excitation • Experimental hutch 2: Depth analysis of in-solid and interface electron states • Spot size: 1.5 μm(V)×20 μm(H) (EH1), 1.5 μm(V)×11 μm(H) / 1.5 μm(V)×1 μm(H)* (EH2) (* Users who wish to use the Φ1 μm focusing and/or mapping of photoelectron should contact the Beamline Scientist before applying for beamtime.) • Temperature range of sample: ~20-400 K (Liquid He flow is used for cooling)
8	BL10XU : High Pressure Research	Crystal structure analysis under high pressure using diamond-anvil cells, in-situ/operando observation of phase transition and compression behavior under extreme conditions, Material sciences under extreme conditions, High pressure Earth and planetary science • Systems for high pressure experiments using diamond anvil cells (<500 GPa) : X-ray flat panel detector, Imaging plate, photon-counting pixel detector with CdTe sensor, Ionization chamber, PIN PD, X-ray focusing lens, Multi-channel collimator, Raman spectroscopy system, pressure measurement system for ruby fluorescence method, Cryostat for high pressure experiment (7-300 K), Laser heating system (1,500-6,000 K), Resistive heating system (300-1,000 K), Gas pressure controller for gas membrane DACs (Please contact to BL scientists about using high speed photon-counting detector, Multi-channel collimator system, and/or Resistive heating system before application.) • In-vacuum undulator and Si (111)/ Si (220) double crystals: 6-61 keV • Typical focused X-ray beam size: ~20 μm(H, V) (EH1). 0.8 μm(V)× 0.9 μm(H) / 1.8 μm(V)×2 μm(H) / 7 μm(V)×9 μm(H) (EH2)

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9	<p>BL13XU : X-ray Diffractions and Scattering I</p> <p>Experimental hutch 1: Versatile Six-axis Diffractometer Experimental hutch 2: Diffraction measurement multi-purpose frame Experimental hutch 3: High-resolution powder X-ray diffraction Experimental hutch 4: Nanobeam X-ray diffraction system Si 111/ 311 double-crystal monochromator Experimental hutch 1: 6-axis X-ray diffractometer (HUBER)/ C-type χ cradle (4 axes for sample, 2 axes for detector), Sample stage (XYZ and swivel), Double slit, Soller slit, Analyzer crystal, Thin film sample heating device (Anton Paar DHS1100, room temperature to 1100°C), Thin film sample heating and cooling device (Anton Paar DCS500, -180 to 500°C) , Small tensile tester (MAX load: 200 N, 2 kN), Various ample atmosphere(Vacuum, N2, He, Al) Scintillation detector (FMB, LaBr3), Ion chamber, 1D detector (6-module of MYTHEN), 2D detector (PILATUS(Si) 300K, 2M) Experimental hutch 2: Sample stage with a hexapod, Robot arm for a detector, 2D detector (PILATUS X 300K, PILATUS X 2M) Experimental hutch 3: Powder Diffractometer equipped with six 2D CdTe photon-counting pixel detectors (Lambda 750 K), Large Area Flat panel detector (XRD1611, 400 x 400 mm²). Sample Changer / Automatic measurement system (100 sample, 100 - 1100 K), Large area load table for various operand measurements(θ, XYZ), low- or high-temperature N2 gas streams devices(90 - 473 K, RT - 1100 K), Remote gas handling system for capillary, Please contact to the responsible beamline scientist, if you want to do extremely low-temperature using cryostat (4 - 300 K), high temperature using Anton Paar furnace and Linkam flat plate furnace(~1300 K, ~1700 K), and In situ powder X-ray diffraction experiment under gas and vapor atmosphere. Experimental hutch 4: Nanobeam X-ray diffraction system, Fresnel zone plate, X-ray compound refractive lenses, HyPix-3000, Ionization chamber, Pi PIN photodiode, Fluorescence detector In-vacuum undulator (5 - 72 keV)</p>	<p>X-ray diffraction and reflectivity measurements, Atomic-scale structural analysis of crystal surfaces and interfaces, ultrathin films, and nanostructures, Residual stress measurement, Time-resolved X-ray diffraction, In-situ process observation using X-ray diffraction, Operando X-ray diffraction, High-resolution powder X-ray diffraction and X-ray total scattering, Structural refinement using Rietveld analysis, In-situ/operando powder X-ray diffraction, Time-resolved powder X-ray diffraction, Analysis of local structures using nanodiffraction</p>

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10	BL14B2 : XAFS II	X-ray imaging, XAFS in a wide energy range (5-72 keV), XAFS of dilute systems and thin films, Time-resolved XAFS by quick scan (Time-resolved QXAFS)
	X-ray imaging camera, XAFS measurement system, Ionization chamber, 19-element Ge solid-state detector (SSD), 7-element SDD, Lytle detector, Conversion electron yield (CEY) detector, Cryostat (10 K-RT), High-temperature cell for transmission (RT-1,000 °C), High-temperature cell for fluorescence (RT-800 °C), Gas supply and exhaust system [Users who wish to use the system should contact the Beamline Scientist (Honma) before applying for beamtime.] Bending magnet (5-72 keV)	
11	BL19B2 : X-ray Diffractions and Scattering II	Residual stress measurement, Structural analysis of thin film, surface and interface, Powder X-ray diffraction, X-ray topography, Ultrasmall-angle X-ray scattering
	Versatile High-throughput diffractometer (powder diffractometer), 6-axis X-ray diffractometer (HUBER)/ C-type χ cradle (4 axes for sample, 2 axes for detector), Sample stage (XYZ and swivel), Double slit, Soller slit, Analyzer crystal, Thin film sample heating device (Anton Paar DHS1100, room temperature to 1100°C), Thin film sample heating and cooling device (Anton Paar DCS500, -180 to 500°C) , Small tensile tester (MAX load: 200 N, 2 kN), Various ample atmosphere (Vacuum, N ₂ , He, Ar), Scintillation detector (FMB, LaBr ₃), Ion chamber, 1D detector (6-module of MYTHEN), 2D detector (PILATUS(Si) 300K), Small-angle X-ray scattering (SAXS) camera with a camera length of 0.7 - 40 m. For powder diffraction and SAXS experiment, fully-automated sample changers are available.	
12	BL20XU : Medical and Imaging II	X-ray micro-/nano-imaging: micro-CT, nano-CT (15-37.7keV), refraction/phase contrast imaging, X-ray diffraction tomography (XRD-CT), microbeam/scanning x-ray microscope Research and development of X-ray optics and optical elements, coherent X-ray optics Ultra small-angle X-ray scattering (USAXS, 23keV)
	High-precision diffractometer for various types of imaging, Liquid-nitrogen-cooled Si(111) double-crystal monochromator (7.62-37.7 keV) or Si(220) double-crystal monochromator (~61 keV), Middle-length undulator beamline (245 m), Beam size: 1.4 mm(H) x 0.7 mm(V) at 1st experimental hut and 4 mm(H) x 2 mm(V) at 2nd experimental hut, High-resolution X-ray imaging detectors (resolution ~1 μ m), Large view field X-ray imaging / XRD detectors (maximum FOV 40mm, resolution 10-20 μ m), Imaging intensifier (Be window, 4-inch type), Grove box for preparing samples (dew point about -60 degrees. installed in the downstream hut outside the storage ring building. Ar atmosphere is available and N ₂ atmosphere also can be used if necessary. Users who wish to use them should contact the Beamline scientist beforehand at least 2 weeks), Integrated measurement including micro-/nano-CTs, XRD and microbeam is available (prior consultation with beamline scientist required) USAXS (23keV, $3.6 \times 10^{-4} < q < 2.9 \times 10^{-3}$ [1/Å], for smaller q-value than 3.6×10^{-4} prior consultation with beamline scientist required)	

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13	BL20B2 : Medical and Imaging II	<p>X-ray micro-CT/laminography, X-ray phase tomography, X-ray real-time imaging(absorption or refraction contrast), ultra-fast X-ray radiography and X-ray micro-angiography. Small-animal experiments for medical research.</p> <p>Research and development of basic techniques for evaluation of optical devices and X-ray imaging</p> <p>High-precision stages for X-ray imaging, General-purpose experimental tables, Long-stroke sample/detector stages, High-resolution X-ray imaging detector (resolution, 1 ~ 10 μm), Wide field of view X-ray imaging detector (50 mm in width), Large-area X-ray imaging detector (flat panel), Medium-length beamline (215 m), Maximum beam size [experimental hutches 2 and 3, 150 mm(H) × 15 mm(V); experimental h1utch 1, 30 mm(H) × 4 mm(V)], Bending magnet (Standard crystal monochromator: 8-72 keV, multilayer monochromator: 40keV, 110keV)</p>
14	BL25SU : Soft X-ray Spectroscopy of Solid	<p>Circular polarized soft X-ray beam generated by twin-helical undulator. Research on electronic states by photoemission spectroscopy (PES), Research on electronic band structures by angle-resolved photoemission spectroscopy (ARPES), Study of magnetic states by magnetic circular dichroism (MCD) of soft X-ray absorption, Analysis of surface atomic arrangement by photoelectron diffraction (PED), Nano-spectroscopic analysis using low-energy/photoemission electron microscope (SPELEEM).</p> <p>A branch: Retarding field analyzer (RFA), Micro-focused soft X-ray PES, Low-energy/photoemission electron microscope</p> <p>B branch: MCD measurement system, Pulsed-magnet XMCD measurement system (In the end of 2022B term, the Nano-XMCD finished operation for public use.)</p> <p>(A branch, 0.12-2 keV; B branch, 0.2-2 keV)</p> <p>Contact the Beamline Scientist of BL25SU before applying for beamtime for cases (1)-(4) below.</p> <p>(1) When you use RFA</p> <p>(2) When you wish to carry out experiments using carry-in devices</p> <p>(3) When you plan to use pulsed-magnet XMCD apparatus (4) When you plan to use SPELEEM apparatus</p>

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15	BL27SU : Soft X-ray Photochemistry	Soft X-ray photoabsorption spectroscopy of dilute samples in partial fluorescence yield mode, Surface and interface analysis using depth-resolved Soft X-ray photoabsorption spectroscopy, Soft X-ray photoabsorption spectroscopy under ambient atmospheric pressure, Spectroscopy using soft X-ray microbeam, Observation of electron state in solids by soft X-ray emission spectroscopy B branch: High-energy soft X-ray beam (2.1-3.3 keV) using Si(111) crystal monochromator -Soft X-ray photoabsorption spectrometer (electron yield mode and partial fluorescence yield mode) -X-ray fluorescence analyzer -Scanning soft X-ray microspectroscopy C Branch: Low-energy soft X-ray beam (0.17-2.2 keV) using grating monochromator -Soft X-ray photoabsorption spectrometer (electron yield mode and partial fluorescence yield mode) -Soft X-ray photoabsorption spectroscopy under ambient atmospheric pressure (Users who wish to use the system should contact the Beamline Scientist (Nitta) before applying for beamtime.) - Soft X-ray emission spectrometer
16	BL28B2 : White Beam X-ray Diffraction	White X-ray diffraction: X-ray topography, Energy-dispersive strain measurement High energy (~200 keV) X-ray microtomography, Automatic high-energy X-ray micro-CT system High-speed X-ray imaging White X-ray topography system, Energy-dispersive XAFS system, Experimental system for biomedical application experiments, Multipurpose diffractometer Bending magnet (White, ≥5 keV) Beam size: 50 mm(H) x 5 mm(V) @white beam, 50 mm(H) x 1.5 mm(V) @200keV
17	BL35XU : Inelastic and Nuclear Resonant Scattering	Phonons in solids and atomic dynamics in disordered materials by inelastic X-ray scattering. Atomic and molecular dynamics by nuclear resonant inelastic scattering and quasi-elastic scattering. Synchrotron-radiation-based Mössbauer spectroscopy. Nuclear excitation. Inelastic X-ray Scattering (IXS) (~1 to 100 nm ⁻¹ , 12 analyzers) • In-vacuum undulator (17.794 and 21.747 keV, Resolution: 3.0 and 1.5 meV) • Spot size: ~Φ80 μm (Φ20 μm with KB setup) Nuclear Resonant Scattering (NRS): Nuclear inelastic scattering spectrometer, Time-domain/Energy-domain Mössbauer spectrometer, Quasi-elastic scattering spectrometer using time domain interferometry In-vacuum undulator (14.4 - 27.8 keV, 43.0 - 100 keV) • Spot size: ~50 (H) x 25 (V) μm at 14.4 keV

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18	BL37XU : Trace Element Analysis	X-ray microbeam/nano-beam spectrochemical analysis, X-ray spectroscopic imaging, Ultratrace-element analysis, High-energy X-ray fluorescence analysis Projection/scanning/imaging XAFS microscopy, High brightness XAFS, Coherent diffraction imaging XAFS microscopy XAFS measurement system, Scanning X-ray microscope, Imaging X-ray microscope, X-ray tomography system, Multipurpose diffractometer, X-ray fluorescence analyzer, Bend crystal Laue analyzer, X-ray shutter Ionization chamber, PIN photodiode, 1-element Ge solid-state detector, 7-element Si drift detector, Indirect conversion X-ray image detector (High speed CMOS camera), Flat-panel detector, 2D pixel array detector In-vacuum undulator, Liquid-nitrogen-cooled double-crystal monochromator (Si(111): 4.5~37.7 keV, Si(511): 12~113 keV), Higher harmonics rejection mirrors (Pt/Ru coated, bent flat mirror for horizontal focusing) Beam size: 1 mm(H)×0.7 mm(V), 100 nm(H)×100 nm(V) (W.D. = 100 mm, 5~55 keV), 500 nm(H)×300 nm(V) (W.D. = 300 mm, 5~30 keV)
19	BL39XU : Magnetic Materials	X-ray magnetic circular dichroism (XMCD) spectroscopy and element-specific magnetometry (ESM), X-ray emission spectroscopy (XES) and its magnetic circular dichroism, XMCD magnetic imaging and local ESM using micro/nanobeam, XAFS microscopy and local ESM, XAFS and XMCD at high pressure, X-ray spectroscopy using variable X-ray polarization (horizontally/perpendicular linear or circular) Diamond circular polarization element (X-ray phase retarder, operable at 5-23 keV) XMCD spectrometer + Magnetic field generator [electromagnet (3.5 T), superconducting magnet (7 T, 2 K)] X-ray emission spectrometer(incident X-rays: 4.92-19 keV, emission X-rays: 4.4-18 keV)(*,**) Cryogenic device [helium-flow cryostat (11-500 K), superconducting magnet (2-300 K), pulse-tube-type cryostat (4-300 K)(*)] High-pressure generator (DAC, atmospheric pressure-180 GPa at RT, atmospheric pressure-40 GPa at low temperature)(*] KB focusing mirror for high-pressure XMCD (beam size, 2(vertical) x 9(horizontal)μm; W.D.=400 mm; 5-9.5 keV)(*] KB focusing mirror for microscopic XMCD and XAFS (beam size, 100-300 nm; W.D.= 80 mm; 5-16 keV)(*] (*)Users who wish to use these devices should contact the Beamline Scientist before applying for beamtime. (**)Some energy ranges are not available.

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20	BL40XU : High Flux	Fast time-resolved X-ray diffraction and scattering experiments, X-ray photon correlation spectroscopy, X-ray fluorescence analysis, Microbeam X-ray diffraction and scattering experiments, Micro-crystallography
Experimental hutch 1: X-ray shutters, Fast CMOS video camera (Orca-Flash 4.0 (Hamamatsu), FASTCAM Mini AX200(Photron), FASTCAM NovaS16(Photron), Flat-panel detector(C9728DK-10, Hamamatsu), Pilatus3 X 100kA (Dectris), Eiger2 S 500k(Dectris), X-ray image intensifier (4 inches, Hamamatsu), Nd:YAG laser (Surelite II-10, Continuum), Small-angle scattering vacuum path (maximum sample/detector distance, 3.5 m), Pinhole optics (typically $\geq 5 \mu\text{m}$, $2 \mu\text{m}$ in special cases), Stopped-flow mixing system (SFM-4000S, BioLogic)		
Experimental hutch 2** : Precision diffractometer, Zone-plate-focusing optics, femtosecond-laser system, EIGER 1M		
*Helical undulator (8-17 keV)		
*Beam size at sample: $250 \mu\text{m}$ (H) x $40 \mu\text{m}$ (V)		
*Flux: 10^{15} photons/s (12 keV)		
*Quasi-monochromatic beams ($\Delta\lambda/\lambda=2\%$) without the need of a monochromator		
**Please contact the beamline scientist, if you submit the beamline proposal for the first time and want to use own experimental devices.		
21	BL40B2 : SAXS BM	Small-angle X-ray scattering (SAXS)
Small-angle scattering camera [Vaccum path length, 250, 500, 1000, 1500, 2000, 3000, 4000, 6000(*) mm]		
Pixel array detector (Pilatus3S 2M, Pilatus100KS and Eiger2 S 500K Dectris Ltd., ModuPIX ADVACAM)		
Imaging plate ditector (R-AXIS VII(*), Rigaku Corporation)		
Flat-panel detector (C9728DK-10, Hamamatsu Photonics K.K., for wide angle)		
Switching mechanism system between SAXS and WAXS (SAXS: 1500, 2000, 3000, 4000 mm for Pilatus2 S 2M; WAXS: 85-170 mm for Eiger2 S 500K)		
Sample-environment equipment: Temperature control (HCS302 and TS62 Instec Inc., 10002L Linkam Sci., Mechanical characterisation system(*) (10073L Linkam Sci.), DSC(*) (FP84HT, Mettler-Toledo International Inc.), DSC(*) (Rigaku Corporation)), Nitrogen gas generator (maximum flow rate: 5 L/min), Automatic cell cleaning system and sample changer(*) (BioCUBE, Xenocs Inc.), Liquid Chromatograph(HPLC)(*) (Prominence, Shimadzu Corp.)		
Bending magnet (6.5-22 keV)		
(*)Users who wish to use these devices should contact the beamline scientist before applying for beamtime.		

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22	BL41XU : Macromolecular Crystallography I Diffractometer for macromolecular crystallography In-vacuum undulator (normal mode, 6.5-17.7 keV; *high-energy mode, 19-35 keV) Beam size (at sample position): 5(H) × 5(V) μm ² ~ 50(H) × 50(V) μm ² (normal mode), 30 × 30 μm ² ~ 300 × 300 μm ² (high energy mode) Hybrid photon counting detector EIGER X 16M (normal mode), EIGER2 X CdTe 4M (high-energy mode) Cryo-cooler (N ₂ gas, ≥100 K; He gas, ≥20 K) Peltier-cooled silicon drift detector SPring-8 precise automatic cryo-sample exchanger (SPACE) *Users who wish to use the high-energy mode should contact the Beamline Scientist before applying for beamtime. Public use of cryogenic transmission electron microscopes, EM01CT (CRYO ARM 300) and EM02CT(CRYO ARM 200), have started in 2021B as an ancillary facility. Please check the following Web-site before using the beamline. http://stbio.spring8.or.jp/index_en.php	Macromolecular crystallography, Micro-crystallography, Ultra-high resolution structural analysis
23	BL43IR : Infrared Materials Science Wavenumber range: 100-20,000 cm ⁻¹ High-spatial-resolution microscope: Objectives (x36(NA=0.5, WD=10 mm), x15(NA=0.4, WD=24 mm), x20(ATR)), Cryostat (4.2 K~400 K), Temperature controlled stage (-190~600°C) Long-working-distance microscope: Objective (x8(NA=0.5, WD=50 mm), Diamond anvil cell+Cryostat (0.4 mm culet/30 GPa, 10~400 K), Cryostat (4.2~400 K) Magneto-optical microscope: Objective (x16(NA=0.3, WD=40 mm), Magnetic field 14 T, Cryostat (4.2~300 K)	Infrared microspectroscopy
24	BL45XU : Macromolecular Crystallography II Diffractometer for macromolecular crystallography In-vacuum undulator (6.5-16.0 keV) Beam size (at sample position): 5(H) × 5(V) μm ² ~ 50(H) × 50(V) μm ² Hybrid photon counting detector PILATUS 6M Cryo-cooler (N ₂ gas, ≥100 K) SPring-8 precise automatic cryo-sample exchanger (SPACE) Please check the following Web-site before using the beamline. http://stbio.spring8.or.jp/index_en.php	Macromolecular crystallography, Micro-crystallography, Automation & High throughput data collection for protein crystallography

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25	BL46XU : HAXPES II	Hard X-ray photoemission spectroscopy Ambient Pressure Hard X-ray Photoemission Spectroscopy
	In-vacuum undulator (5.5-37 keV) Double channel cut monochromator(DCCM): Si 220 x 2, Si 311 x 2 • Experimental hutch 1: Hard X-ray photoelectron spectroscopy Hard X-ray photoemission spectroscopy system (Scienta Omicron R4000-10kV), hn=6, 8, 10 keV, Spot size: 1 μm(V)×30 μm(H) • Experimental hutch 2: Ambient Pressure Hard X-ray Photoemission Spectroscopy Hard X-ray photoemission spectroscopy system (Scienta Omicron R4000-Hipp2), hn=6, 8, 10 keV, Spot size: 1 μm(V)×10 μm(H), Measurement in gas atmosphere* *Please contact to beamline scientists regarding the type of gas and pressure.	
26	BL47XU : Micro-CT	X-ray optics, Planetary science, Materials science, Applied materials science
	In-vacuum undulator (5.2-37.7 keV, horizontal polarization) High-spatial-resolution micro-tomography system, High speed imaging system, Hard X-ray microbeam/scanning microscopy experiment Please contact to beamline scientists before putting on a new proposal to BL47XU.	

■ RIKEN Beamlines

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Experimental station/system		
Light source (energy range at sample position, etc.)		
27	BL05XU : R&D-ID I	Structural analysis by small and wide angle X-ray scattering
	Photon energy: 7~15 keV Photon flux < 1×10^{13} photons/s (12.4 keV) Sample-to-detector distance: ~10 cm - 4 m For other conditions and facilities, contact the Beamline Scientist beforehand.	
28	BL07LSU : R&D-ID II	Development of soft X-ray optical system requiring long undulator radiation
	6-segment horizontal and vertical figure-8 undulator, energy range 250~2000 eV (horizontal and vertical polarization) Energy resolution (designed value) $E/\Delta E > 10^4$ Beam height 1417 mm Beam size > several mm (without refocusing mirror) Flux $> 10^{11}$ ph/sec/0.01%BW When applying for public use of BL07LSU, it is necessary to have a meeting with the BL representative (RIKEN M.Oura : oura@spring8.or.jp) in advance.	

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29	BL17SU : RIKEN Coherent Soft X-ray Spectroscopy	>Scanning soft x-ray spectromicroscope --- A3 station Microspectroscopic observation of sample surface under conditions ranging from low vacuum to helium atmosphere is available. >Versatile photoemission electron microscope --- Bc station Electronic/magnetic states imaging (resolving power: better than 100 nm) and its time-resolved measurements
Helical-8 undulator, Energy range for A and B branches (225* - 2,000 eV) (*225 eV for Circularly polarized light, 272 eV for Horizontally polarized light, 136 eV for Vertically polarized light) , Energy resolution (E/dE ~10,000), Beam size at sample position [$\sim 30 \mu\text{m(H)} \times 4 \mu\text{m(V)}$] Before applying for public use of BL17SU, contact the following persons in charge of respective equipment. Scanning soft x-ray spectromicroscope: Suga (hiroki-suga@spring8.or.jp) at JASRI/RIKEN, Oura at RIKEN (oura@spring8.or.jp) versatile photoemission electron microscope: Ohkochi (o-taku@spring8.or.jp) at JASRI/RIKEN Free space where users can bring their systems: Oura (oura@spring8.or.jp) at RIKEN		
30	BL19LXU : RIKEN SR Physics	Research on physical science requiring ultrahigh-brilliance X-ray beam from long undulator
Experimental station/system: 5(W) \times 3.4(D) \times 4.5(H) m ³ open hutch, Optical bench, PIN photodiode, Scintillation counter, Ionization chamber, Stepping motor drivers and controllers, NIM Bin power supply, Counter, Trigger signal synchronized with RF of storage ring Light source (energy range at sample position, etc.): In-vacuum undulator (7.1-18 keV, 22-51 keV, flux of ~ 1014 photons/s at 12.4 keV) For other conditions and facilities, contact the Beamline Scientist beforehand.		
31	BL26B1 : RIKEN Structural Genomics I	Structural biology research based on single-crystal X-ray diffraction
Area detector [Dectris EIGER X], Goniometer with horizontal spindle axis, Blowing cryo-cooler (95 K-RT), Sample changer SPACE, Bending magnet (6.5-15.5 keV) Please check the following Web-site before using the beamline. http://stbio.spring8.or.jp/index_en.php		
32	BL29XU : RIKEN Coherent X-ray Optics	Research on physical science using long beamline and coherent X-ray beam
Experimental station/system: Open hutches with size of 5(W) \times 3(D) \times 3.3(H) m ³ [EH1], 10(W) \times 4.25(D) \times 4.5(H) m ³ [EH2], 8(W) \times 4(D) \times 3.3(H) m ³ [EH3], and 6(W) \times 3(D) \times 3.3(H) m ³ [EH4], Optical benches, PIN photodiodes, Scintillation counters, Ionization chambers, Stepping motor drivers and controllers, NIM Bin, Power supply, Counter, Visible-conversion X-ray camera, Trigger signal synchronized with RF of storage ring Light source (energy range at sample position, etc.): In-vacuum undulator (1st order harmonics : 5-19 keV, 3rd order harmonics : 15-56 keV, flux of $\sim 6 \times 10^{13}$ photons/s at 10 keV), silicon monochromator(111 plane)(4.4 ~ 37.8 keV) For other conditions and facilities, contact the Beamline Scientist beforehand.		

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Light source (energy range at sample position, etc.)		
33	BL32XU : RIKEN Targeted Proteins	Structural biology, X-ray crystallography for biopolymer, Micro-crystallography for ultrafine proteins
Experimental station/system: EEM focusing mirror unit, Ultralow-eccentricity high-precision goniometer, Ultralow-temperature He blower, Hybrid photon counting detector (DECTRIS EIGER X 9M), Large-volume sample mounting robot with applicability to Hampton pins		
Light source (energy range at sample position, etc.):		
[Light source] Hybrid undulator		
[Beam size at sample position] 1×1-10×10 μm ²		
[Flux of 1 μm beam] 7 × 10 ¹⁰ photons/s at 12.4 keV		
[Energy range] 9-18 keV (If you prefer to use lower energy X-ray than 9 keV, please contact us)		
Please check the following Web-site before using the beamline.		
http://stbio.spring8.or.jp/index_en.php		
34	BL36XU : RIKEN Materials ScienceII	Time-resolved QXAFS using tapered-Undulator beam
[Energy region] 4.5-35 keV, [beam size] 40 μm(V)×500 μm(H), 100 nm(V)×100 nm(H), [time resolution] QXAFS(20 ms).		
[light source and optics] In-vacuum tapered undulator, channel-cut crystal monochromators (Si(111), Si(220)), Rh/Pt coated vertical/horizontal focusing mirrors, Rh/Pt coated KB mirrors(4.5-35 keV).		
[Measurement system] Transmission XAFS measurement system, 4-element SDD, PILATUS 300KW, 4-element Merlin detector, indirect X-ray image detector		
In BL36XU, only Quick XAFS apparatus is open for public use. When you apply for public use of BL36XU, please contact to the beamline staff beforehand.		
35	BL38B1 : RIKEN Structural Biology I	Small Angle X-ray Scattering
Bending Magnet(6.5~15.5 keV) *User operation is only 12.4 keV or 15.5 keV.		
Camera length; 300, 2500 mm		
Detector; DECTRIS PILATUS3X 2M., HPLS system for SEC-SAXS		
*Use only BioSAXS.		
36	BL43LXU : RIKEN Quantum NanoDynamics	meV Scale IXS for atomic dynamics
Energy: 14.4-26 keV (Fundamental), meV Spectrometer for atomic dynamics		
37	BL44B2 : RIKEN Materials Science I	Structural analysis of periodic and aperiodic systems by total scattering
Wavelength: 0.41~0.8 Å		
Instrument: Two-axis powder diffractometer (2θ range: 0.5~153°, 2θ step: 0.01°)		
Temperature: -180~800 °C		